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Specification for Approval

Customer:	
Model Name:	

Sı	upplier Approv	Customer approval	
R&D Designed	R&D Approved	QC Approved	
Peter	Peng Jun		

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Revision Record

REV NO.	REV DATE	CONTENTS	Note
Α	2021-11-19	NEW ISSUE	

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1. Scope

This specification defines general provisions as well as inspection standards for TFT module supplied by AMSON electronics.

If the event of unforeseen problem or unspecified items may occur, naturally shall negotiate and agree to solution.

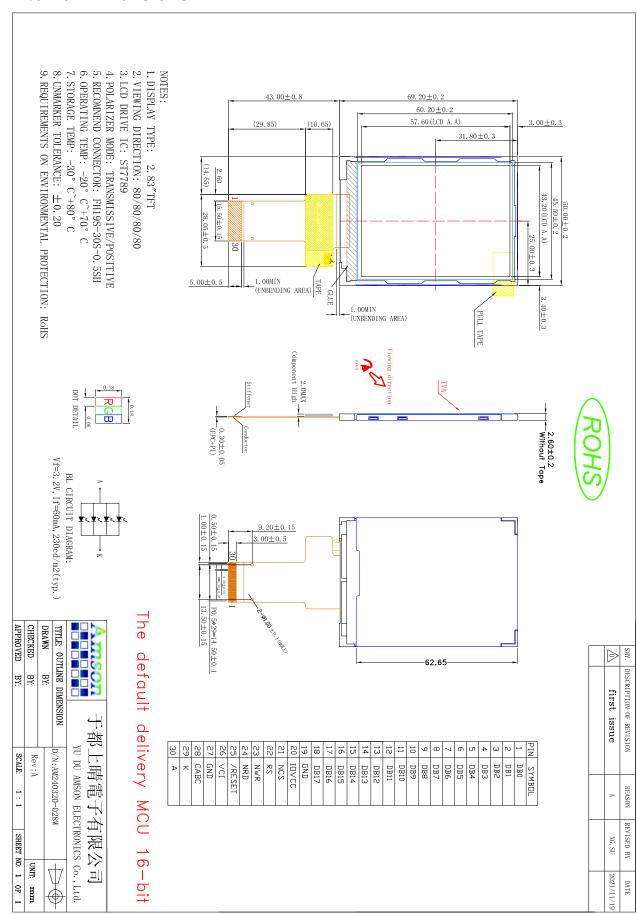
2. General Information

ITEM	STANDARD VALUES	UNITS
LCD type	28"TFT	
Dot arrangement	240(RGB)×320	dots
Color filter array	RGB vertical stripe	
Display mode	TN / Transmission / Normally White	-
Viewing Direction	80/80/80	
Driver IC	ST7789V	
Module size	50.0W)×69.2 (H)×2.6(T)	mm
Active area	43.2 (W)×57.6 (H)	mm
Dot pitch	0.18 (W)×0.18(H)	mm
Interface	MCU 16-bit Interface	
Operating temperature	-20 ~ +70	°C
Storage temperature	-30 ~ +80	°C
Back Light	4White LED	

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3. External Dimensions





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4. Interface Description

PIN NO.	PIN NAME	DESCRIPTION			
1-18	DB0-DB17	DATA BUS			
19	GND	System Ground			
20	IOVCC	Power supply for logic.			
21	NCS	Input pin for chip selection signal.			
22	RS	Register select pin. Low: Index/status, High: Control.			
23	NWR	Write enable pin I80 parallel bus system interface.			
24	NRD	Read enable pin I80 parallel bus system interface.			
25	/RESET	Reset pin. Initializes the IC, when this signal is low. Must be reset after power is stable.			
26	VCI	Power supply for analog.			
27	GND	System Ground			
28	CABC	CABC backlight control PWM signal output			
29	K	LED backlight (Cathode).			
30	А	LED backlight (Anode).			



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5. Absolute Maximum Ratings

Item	Symbol	Min.	Max.	Unit
Logic Supply Voltage	IOVCC	-0.3	4.6	V
Analog Supply Voltage	VCI	-0.3	4.6	V
Input Voltage	Vin	-0.3	IOVCC +0.3	V
Operating Temperature	Тор	-20	70	°C
Storage Temperature	Тѕт	-30	80	°C
Storage Humidity	HD	20	90	%RH

6. DC Characteristics

Item	Symbol	Min.	Тур.	Max.	Unit	Remark
Logic Supply Voltage	IOVCC	1.65	2.8	3.3	V	-
Analog Supply Voltage	VCI	2.5	2.8	3.3	V	-
Input High Voltage	V _{IH}	0.7VCI	-	IOVCC	V	-
Input Low Voltage	V _{IL}	GND	-	0.3 IOVCC	V	-
Output High Voltage	V_{OH}	0.8 VCI	-	IOVCC	V	-
Output Low Voltage	V _{OL}	GND	-	0.2 IOVCC	V	-
I/O Leak Current	lu	-1	-	1	uA	-

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7. Timing Characteristics

7.1 MCU 16birt Interface Timing Characteristics

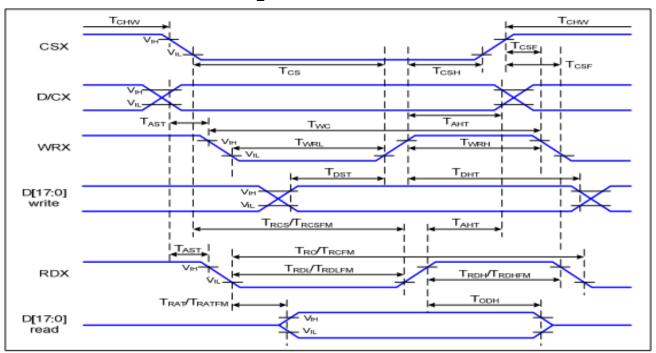


Figure 1 Parallel Interface Timing Characteristics (8080-Series MCU Interface)

VDDI=1.65 to 3.3V, VDD=2.4 to 3.3V, AGND=DGND=0V, Ta= -30 to 70 ℃

. .		Description Min. May Unit Descri				
Signal	Symbol	Parameter	Min	Max	Unit	Description
D/CX	T _{AST}	Address setup time			ns	_
DIOX	T _{AHT}	Address hold time (Write/Read)	10		ns	_
	T _{CHW}	Chip select "H" pulse width	0		ns	
	T _{CS}	Chip select setup time (Write)	15		ns	
CSX	T _{RCS}	Chip select setup time (Read ID)	45		ns	
CSA	T _{RCSFM}	Chip select setup time (Read FM)	355		ns	_
	T _{CSF}	Chip select wait time (Write/Read)	10		ns	
	T _{CSH}	Chip select hold time	10		ns	
	T _{wc}	Write cycle	66		ns	
WRX	T _{WRH}	Control pulse "H" duration	15		ns	
	T _{WRL} Control pulse "L" duration		15		ns	
	T _{RC}	Read cycle (ID)			ns	
RDX (ID)	T _{RDH}	Control pulse "H" duration (ID)	90		ns	When read ID data
	T _{RDL} Control pulse "L" duration (ID)		45		ns	
RDX	T _{RCFM}	T _{RCFM} Read cycle (FM)			ns	When read from
	T _{RDHFM}	Control pulse "H" duration (FM)	90		ns	frame memory
(FM) T _{RDLFM}		Control pulse "L" duration (FM)	355		ns	name memory
D[17:0]	T _{DST}	Data setup time	10		ns	For CL=30pF



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T _{DHT}	Data hold time	10		ns
T_RAT	Read access time (ID)		40	ns
T _{RATFM}	Read access time (FM)		340	ns
Торн	Output disable time	20	80	ns

Table 4 8080 Parallel Interface Characteristics

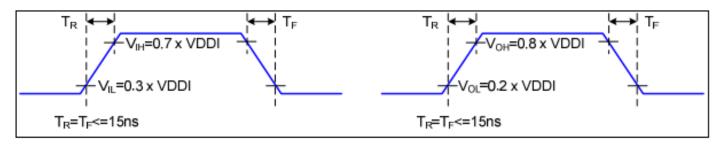


Figure 2 Rising and Falling Timing for I/O Signal

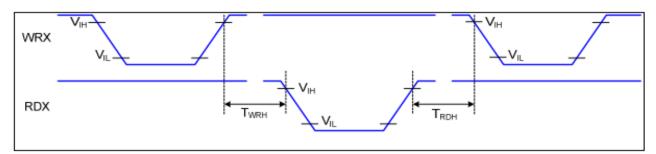


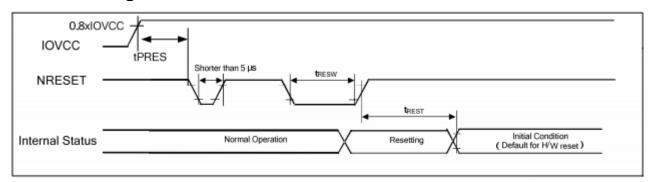
Figure 3 Write-to-Read and Read-to-Write Timing

Note: The rising time and falling time (Tr, Tf) of input signal and fall time are specified at 15 ns or less. Logic high and low levels are specified as 30% and 70% of VDDI for Input signals.

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7.2 Reset Timing Characteristics

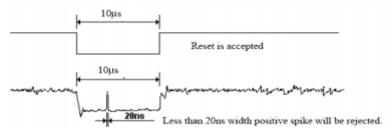


Symbol	Parameter	Related		Spec.		Note	Unit
Symbol	Farameter	Pins	Min. Typ. Max.		Min. Typ. Max.		Oilit
tRESW	Reset low pulse width ⁽¹⁾	NRESET	10	-	-	-	μs
tREST	Reset complete time(2)	-	5	-		When reset applied during STB OUT mode	ms
IKEST	Reset complete time	-	120	-		When reset applied during STB mode	ms
tPRES	Reset goes high level after Power on time	NRESET & IOVCC	1	-	-	Reset goes high level after Power on	ms

Note: (1) Spike due to an electrostatic discharge on NRESET line does not cause irregular system reset according to the table below.

NRESET Pulse	Action
Shorter than 5 µs	Reset Rejected
Longer than 10 µs	Reset
Between 5 µs and 10 µs	Reset Start

- (2) During the resetting period, the display will be blanked (The display is entering blanking sequence, which maximum time is 120 ms, when Reset Starts in STB Out -mode. The display remains the blank state in STB -mode) and then return to Default condition for H/W reset.
- (3) During Reset Complete Time, VMF value in OTP will be latched to internal register during this period. This loading is done every time when there is H/W reset complete time (tREST) within 5ms after a rising edge of NRESET.
- (4) Spike Rejection also applies during a valid reset pulse as shown below:

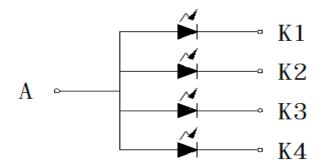


(5) It is necessary to wait 5msec after releasing !RES before sending commands. Also STB Out

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8. Backlight Characteristics



Item	Symbol	MIN	TYP	MAX	UNIT	Test Condition
Supply Voltage	Vf	2.9	3.2	3.5	V	If=80mA
Supply Current	If	-	80	-	mA	-
Luminous Intensity for LCM	-	180	230		cd/m ²	If=80mA
Uniformity for LCM	-	80		-	%	lf=80mA
Life Time	-	20000		-	Hr	If=80mA
Backlight Color	White					



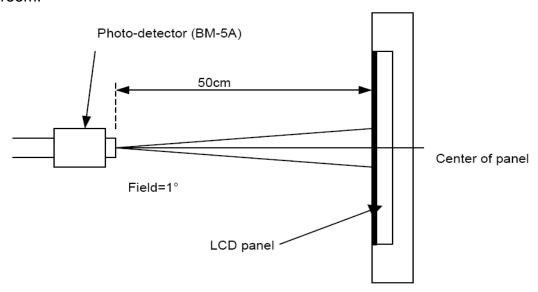
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9. Optical Characteristics

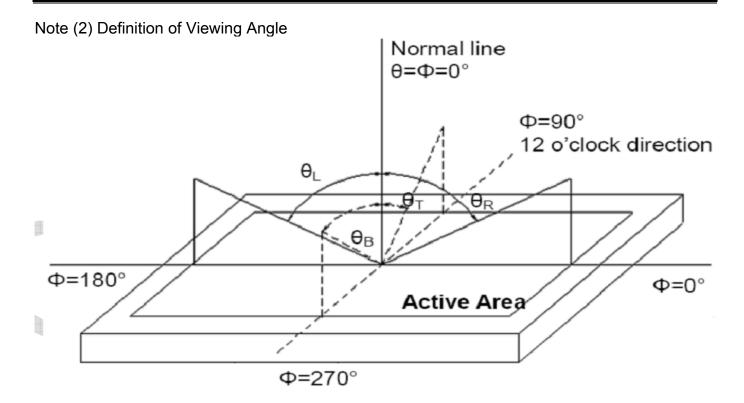
Item	Conditions		Min.	Тур.	Max.	Unit	Note	
	l la via a satal	θL	-	80	-	degree		
Viewing Angle	Horizontal	θR	-	80	-		(1) (2) (6)	
(CR>10)	Vertical	θт	-	80	-		(1),(2),(6)	
	vertical	θв	-	80	-			
Contrast Ratio	Center		-	500	-	-	(1),(3),(6)	
Response Time	Rising + Falling		-	16	-	ms	(1),(4),(6)	
	Red x			TBD		-		
CF Color Chromaticity (CIE1931)	Red y	Red y Green x		TBD		-		
	Green x			TBD		-		
	Green y			TBD	Тур.	-	(1), (6)	
	Blue x		Тур.	TBD		-		
	Blue y	-0.05		TBD	+0.05	-		
	White x			TBD		-		
	White y			TBD		-		

Note (1) Measurement Setup: The LCD module should be stabilized at given temp. 25°C for 15 minutes to avoid abrupt temperature change during measuring. In order to stabilize the luminance, the measurement should be executed after lighting backlight for 15 minutes in a windless room.



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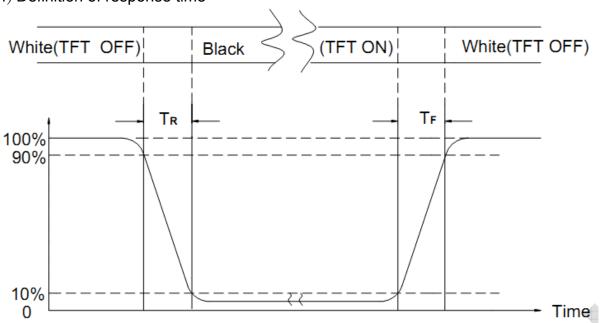


Note (3) Definition of Contrast Ratio (CR)

The contrast ratio can be calculated by the following expression Contrast Ratio (CR) = L63 / L0

L63: Luminance of gray level 63, L0: Luminance of gray level 0

Note (4) Definition of response time



Note (5) Definition of Transmittance (Module is without signal input)

Transmittance = Center Luminance of LCD / Center Luminance of Back Light x 100%

Note (6) Definition of color chromaticity (CIE1931)

Color coordinates measured at the center point of LCD



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10. Reliability Test Conditions and Methods

NO.	TEST ITEMS	TEST CONDITION	INSPECTION AFTER TEST	
	High Temperature Storage	80°C±2°C×96Hours		
	Low Temperature Storage	-30°C±2°C×96Hours	la an artista after O. Alsaura	
	High Temperature Operating	70°C±2°C×96Hours	Inspection after 2~4hours storage at room temperature, the samples	
	Low Temperature Operating	-20°C±2°C×96Hours	should be free from defects: 1, Air bubble in the LCD.	
	Temperature Cycle(Storage)	-20°C \longrightarrow 25°C \longrightarrow 70°C (30min) (30min) 1cycle Total 10cycle	 Seal leak. Non-display. Missing segments. Glass crack. Current IDD is twice 	
	Vibration Test	Frequency:10Hz~55Hz~10Hz Amplitude:1.5MM X,Y,Z direction for total 3hours (packing condition test will be tested by a carton)	higher than initial value. 7, The surface shall be free from damage. 8, The electric characteristic requirements shall be satisfied.	
	Drooping Test	Drop to the ground from 1M height one time every side of carton. (packing condition test will be tested by a carton)	oriali de dationea.	

REMARK:

- 1, The Test samples should be applied to only one test item.
- 2, Sample side for each test item is 5~10pcs.
- 3, For Damp Proof Test, Pure water(Resistance $> 10 \text{M}\Omega$) should be used.
- 4,In case of malfunction defect caused by ESD damage, if it would be recovered to normal state after resetting, it would be judge as a good part.
- 5, EL evaluation should be accepted from reliability test with humidity and temperature: Some defects such as black spot/blemish can happen by natural chemical reaction with humidity and Fluorescence EL has.
- 6, Failure Judgment Criterion: Basic Specification Electrical Characteristic, Mechanical Characteristic, Optical Characteristic.



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11. Inspection Standard

11.1. QUALITY:

THE QUALITY OF GOODS SUPPLIED TO PURCHASER SHALL COME UP TO THE FOLLOWING STANDARD.

11.1.1. THE METHOD OF PRESERVING GOODS

AFTER DELIVERY OF GOODS FROM AMSON TO PURCHASER. PURCHASER SHALL CONTROL THE LCM AT -10 °C TO 40 °C ,AND IT MIGHT BE DESIRABLE TO KEEP AT THE NORMAL ROOM TEMPERATURE AND HUMIDITY UNTIL INCOMING INSPECTION OR THROWING INTO PROCESS LINE.

11.1.2. INCOMING INSPECTION

(A) THE METHOD OF INSPECTION

IF PURCHASER MAKE AN INCOMING INSPECTION, A SAMPLING PLAN SHALL BE APPLIED ON THE CONDITION THAT QUALITY OF ONE DELIVERY SHALL BE REGARDED AS ONE LOT.

(B) THE STANDARD OF QUALITY

ISO-2859-1 (SAME AS MIL-STD-105E), LEVEL II SINGLE PLAN.

CLASS	AQL(%)
CRITICAL	0.4 %
MAJOR	0.65 %
MINOR	1.5 %
TOTAL	1.5 %

EVERY ITEM SHALL BE INSPECTED ACCORDING TO THE CLASS.

(C) MEASURE

IF AS THE RESULT OF ABOVE RECEIVING INSPECTION, A LOT OUT IS DISCOVERED. PURCHASER SHALL BE INFORM SELLER OF IT WITHIN SEVEN DAYS. BUT FIRST SHIPMENT WITHIN FOURTEEN DAYS.

11.1.3. WARRANTY POLICY

AMSON WILL PROVIDE ONE-YEAR WARRANTY FOR THE PRODUCTS ONLY IF UNDER SPECIFICATION OPERATING CONDITIONS. AMSON WILL REPLACE NEW PRODUCTS FOR THESE DEFECT PRODUCTS WHICH UNDER WARRANTY PERIOD AND BELONG TO THE RESPONSIBILITY OF AMSON.

11.2. CHECKING CONDITION

- 11.2.1. CHECKING DIRECTION SHALL BE IN THE 45 DEGREE AREA TO FACE THE SAMPLE.
- 11.2.2. CHECKER SHALL SEE OVER 300±25 mm. WITH BARE EYES FAR FROM SAMPLE AND USING 2 PCS. OF 20W FLUORESCENT LAMP.



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11.3. INSPECTION PLAN:

11.0. II401 LO	TION PLAN :		
CLASS	ITEM	JUDGEMENT	CLASS
PACKING &	OUTSIDE AND INSIDE PACKAGE	"MODEL NO." , "LOT NO." AND "QUANTITY" SHOULD INDICATE ON THE PACKAGE.	Minor
INDICATE	2. MODEL MIXED AND QUANTITY	OTHER MODEL MIXEDREJECTED QUANTITY SHORT OR OVERREJECTED	Critical
	3. PRODUCT INDICATION	"MODEL NO." SHOULD INDICATE ON THE PRODUCT	Major
ASSEMBLY	DIMENSION, LCD GLASS SCRATCH AND SCRIBE DEFECT.	ACCORDING TO SPECIFICATION OR DRAWING.	Major
	5. VIEWING AREA	POLARIZER EDGE OR LCD'S SEALING LINE IS VISABLE IN THE VIEWING AREAREJECTED	Minor
	6. BLEMISH - BLACK SPOT - WHITE SPOT IN THE LCD AND LCD GLASS CRACKS	ACCORDING TO STANDARD OF VISUAL INSPECTION(INSIDE VIEWING AREA)	Minor
APPEARANCE	7. BLEMISH - BLACK SPOT WHITE SPOT AND SCRATCH ON THE POLARIZER	ACCORDING TO STANDARD OF VISUAL INSPECTION(INSIDE VIEWING AREA)	Minor
	8. BUBBLE IN POLARIZER	ACCORDING TO STANDARD OF VISUAL INSPECTION(INSIDE VIEWING AREA)	Minor
	9. LCD'S RAINBOW COLOR	STRONG DEVIATION COLOR (OR NEWTON RING) OF LCDREJECTED. OR ACCORDING TO LIMITED SAMPLE (IF NEEDED, AND INSIDE VIEWING AREA)	Minor
	10. ELECTRICAL AND OPTICAL CHARACTERISTICS (CONTRAST, VOP, CHROMATICITY ETC)	ACCORDING TO SPECIFICATION OR DRAWING. (INSIDE VIEWING AREA)	Critical
ELECTRICAL	11.MISSING LINE	MISSING DOT: LINE: CHARACTERREJECTED	Critical
	12.SHORT CIRCUIT- WRONG PATTERN DISPLAY	NO DISPLAY - WRONG PATTERN DISPLAY - CURRENT CONSUMPTION OUT OF SPECIFICATION REJECTED	Critical
	13. DOT DEFECT (FOR COLOR AND TFT)		Minor



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NO. CLASS	11.4	STANI	DARD OF VISUAL INSPECT	ION			
DIAMETER (mm.) ACCEPTABLE QTY	NO.	CLASS	ITEM	JUDGEMENT			
BLACK AND WHITE SPOT FOREIGN MATERIEL DUST IN THE CELL BLEMISH SCRATCH 11.4.2 MINOR BUBBLE IN POLARIZER DENT ON POLARIZER DENT ON POLARIZER Dot Defect Dot Defect Dot Defect Dot Defect BLACK AND WHITE SPOT FOREIGN MATERIEL DUST IN THE CELL BLEMISH SCRATCH DIAMETER ACCEPTABLE QTY				(A) ROUND TYPE: unit : mm.			
BLACK AND WHITE SPOT FOREIGN MATERIEL DUST IN THE CELL BLEMISH SCRATCH 11.4.1 MINOR BUBBLE IN POLARIZER DENT ON POLARIZER DENT ON POLARIZER Dot Defect Dot D				DIAMETER (mm.) ACCEPTABLE Q'TY			
BLACK AND WHITE SPOT FOREIGN MATERIEL DUST IN THE CELL BLEMISH SCRATCH 11.4.1 MINOR BUBBLE IN POLARIZER DENT ON POLARIZER Dot Defect Dot Defect Dot Defect Dot Defect BLEMSH SCRATCH BUBBLE IN POLARIZER DENT ON POLARIZER Dent on Polarizer Dot Defect Dot Defect Dot Defect Dot Defect Dot Defect Dot Defect BUBBLE IN POLARIZER Dot Defect Dot D				Φ \leq 0.1 DISREGARD			
Til.4.1 MINOR FOREIGN MATERIEL DUST IN THE CELL BLEMISH SCRATCH SC			BLACK AND WHITE SPOT	$0.1 < \Phi \leq 0.25$ 3 (Distance>5mm)			
11.4.1 MINOR DUST IN THE CELL BLEMISH SCRATCH				0.25 < Ф 0			
BLEMISH SCRATCH (B) LINEAR TYPE: Unit: mm. LENGTH WIDTH ACCEPTABLE QTY W ≤ 0.03 DISREGARD L ≤ 5.0 0.03 < W ≤ 0.07 3 (Distance>5mm) 0.07 < W FOLLOW ROUND TYPE Unit: mm. DIAMETER ACCEPTABLE QTY DIAMET	11.4.1	MINOR		NOTE: Φ=(LENGTH+WIDTH)/2			
SCRATCH LENGTH WIDTH ACCEPTABLE Q'TY				(B) LINEAR TYPE: unit : mm.			
L ≤ 5.0 0.03 < W ≤ 0.07 3 (Distance>5mm) 0.07 < W FOLLOW ROUND TYPE Unit : mm. DIAMETER ACCEPTABLE Q'TY DENT ON POLARIZER DENT ON POLARIZER DENT ON POL							
Unit : mm. DIAMETER ACCEPTABLE Q'TY DENT ON POLARIZER DENT ON POLARIZER DOT DEFECT Dot Defect Items ACC. Q'TY							
unit : mm. DIAMETER ACCEPTABLE Q'TY DENT ON POLARIZER DENT ON POLARIZER DOT Defect Items ACC. Q'TY							
DIAMETER ACCEPTABLE Q'TY □ □ □ □ □ □ □ □ □ □ □ □ □ □ □ □ □ □ □				0.07 < W FOLLOW ROUND TYPE			
DIAMETER ACCEPTABLE Q'TY Φ ≤ 0.2 DISREGARD 0.2 < Φ ≤ 0.5 2 (Distance>5mm) 0.5 < Φ Dot Defect Diameter Acceptable Q'TY							
BUBBLE IN POLARIZER DENT ON POLARIZER Dot Defect Items							
DENT ON POLARIZER D.2 < Φ ≤ 0.5 2 (Distance>5mm) D.5 < Φ Dot Defect Dark dot N≤ 4 Dark dot N≤ 1 Dark dot Dark							
Dot Defect State		MINOD					
Dot Defect Items	11.4.2	MINOR					
Dot Defect Bright dot N≤ 4 Dark dot N≤ 4 Pixel Define: Pixel Pixel Dot → Dot				0.5 < Φ 0			
which LCD panel is displaying under pure red, green	11.4.3	MINOR	Dot Defect	Bright dot N≤ 4 Dark dot N≤ 4 Pixel Define: Pixel Pix			



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NO.	CLASS	ITEM	JUDGEMEN	Т
11.4.4	MINOR	LCD GLASS CHIPPING	F S	Y > S Reject
11.4.5	MINOR	LCD GLASS CHIPPING	SI	X or Y > S Reject
11.4.6	MAJOR	LCD GLASS GLASS CRACK	Y Y	Y > (1/2) T Reject
11.4.7	MAJOR	LCD GLASS SCRIBE DEFECT	A + B	1. a> L/3 , A>1.5mm. Reject 2. B: ACCORDING TO DIMENSION
11.4.8	MINOR	LCD GLASS CHIPPING (ON THE TERMINAL AREA)	T	$\Phi = (x+y)/2 > 2.5 \text{ mm}$ Reject
11.4.9	MINOR	LCD GLASS CHIPPING (ON THE TERMINAL SURFACE)	TZX	Y > (1/3) T Reject
11.4.10	MINOR	LCD GLASS CHIPPING	T Z	Y > T Reject



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12. Handling Precautions

12.1 Mounting method

The LCD panel of AMSON TFT module consists of two thin glass plates with polarizes which easily be damaged. And since the module in so constructed as to be fixed by utilizing fitting holes in the printed circuit board.

Extreme care should be needed when handling the LCD modules.

12.2 Caution of LCD handling and cleaning

When cleaning the display surface, Use soft cloth with solvent

[Recommended below] and wipe lightly

- Isopropyl alcohol
- Ethyl alcohol

Do not wipe the display surface with dry or hard materials that will damage the polarizer surface.

Do not use the following solvent:

- Water
- Aromatics

Do not wipe ITO pad area with the dry or hard materials that will damage the ITO patterns Do not use the following solvent on the pad or prevent it from being contaminated:

- Soldering flux
- Chlorine (CI), Sulfur (S)

If goods were sent without being silicon coated on the pad, ITO patterns could be damaged due to the corrosion as time goes on.

If ITO corrosion happen by miss-handling or using some materials such as Chlorine (CI), Sulfur (S) from customer, Responsibility is on customer.

12.3 Caution against static charge

The LCD module use C-MOS LSI drivers, so we recommended that you:

Connect any unused input terminal to VDD or GND, do not input any signals before power is turned on, and ground your body, work/assembly areas, and assembly equipment to protect against static electricity.

12.4 packing

- Module employs LCD elements and must be treated as such.
- Avoid intense shock and falls from a height.
- To prevent modules from degradation, do not operate or store them exposed direct to sunshine or high temperature/humidity

12.5 Caution for operation

- It is an indispensable condition to drive LCD's within the specified voltage limit since the higher voltage then the limit cause the shorter LCD life.
- An electrochemical reaction due to direct current causes LCD's undesirable deterioration, so that the use of direct current drive should be avoided.
- Response time will be extremely delayed at lower temperature then the operating temperature range and on the other hand at higher temperature LCD's how dark color in them. However those phenomena do not mean malfunction or out of order with LCD's, which will come back in the specified operation temperature.
- If the display area is pushed hard during operation, some font will be abnormally displayed but it resumes normal condition after turning off once.
- Slight dew depositing on terminals is a cause for electro-chemical reaction resulting in terminal open circuit.
 - Usage under the maximum operating temperature, 50%Rh or less is required.



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12.6 storing

In the case of storing for a long period of time for instance, for years for the purpose or replacement use, the following ways are recommended.

- Storage in a polyethylene bag with the opening sealed so as not to enter fresh air outside in it. And with no desiccant.
- Placing in a dark place where neither exposure to direct sunlight nor light's keeping the storage temperature range.
- Storing with no touch on polarizer surface by the anything else.
 [It is recommended to store them as they have been contained in the inner container at the time of delivery from us.

12.7 Safety

- It is recommendable to crash damaged or unnecessary LCD's into pieces and wash off liquid crystal by either of solvents such as acetone and ethanol, which should be burned up later.
- When any liquid leaked out of a damaged glass cell comes in contact with your hands, please wash it off well with soap and water.

13. Precaution for Use

13.1

A limit sample should be provided by the both parties on an occasion when the both parties agreed its necessity. Judgment by a limit sample shall take effect after the limit sample has been established and confirmed by the both parties.

13.2

On the following occasions, the handing of problem should be decided through discussion and agreement between responsible of the both parties.

- When a question is arisen in this specification.
- When a new problem is arisen this is not specified in this specification.
- When an inspection specifications change or operating condition change in customer is reported to AMSON TFT and some problem is arisen in this specification due to the change.
- When a new problem is arisen at the customer's operating set for sample evaluation in the customer site.

14. Packing Method

TBD